Se	arch No	otes

Application/Control No.	Applicant(s)/Patent une Reexamination	der
10/646,695	NAKAI ET AL.	
Examiner	Art Unit	
Chong H. Kim	3682	

	SEAR	CHED	
Class	Subclass	Date	Examiner
184	6.5-6.8	6/24/2006	СК
123	196A 196R		
	196M		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEAR (INCLUDING SE	CH NOTES EARCH STR	ATEGY)	
	D	ATE	EXMR
EAST text search	6/2	4/2006	CK